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PATENT ABSTRACTS OF JAPAN

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(71)Applicant : MITSUBISHI ELECTRIC CORP

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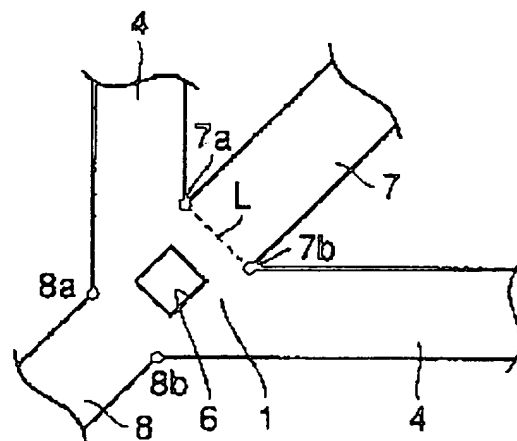
(72)Inventor : YASUDA NAOTSUGU
TONE YOSHIMORI

54) SEMICONDUCTOR DEVICE

57)Abstract:

PROBLEM TO BE SOLVED: To provide a semiconductor device having a resin peeling prevention hole and provided with a lead frame difficult to concentrate deformation in the neighborhood thereof.

SOLUTION: The resin peeling prevention hole 5 is provided on the intersection part 1 of a reinforcing frame 4 and an inside hanging lead in the lead frame, and positioned on the intersection part of the area of the contrary side of a die pad rather than a line L connecting first and second inside hanging lead root boundary points 7a, 7b being a point in which the reinforcing frame continues to both the side parts of an inside hanging lead extending from the intersection part.



LEGAL STATUS

Date of request for examination]

Date of sending the examiner's decision of rejection]

Kind of final disposal of application other than the
examiner's decision of rejection or application
converted registration]

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